Search Notes			

Application No.	Applicant(s)	
10/622,466	NA ET AL.	
Examiner	Art Unit	
Stophon W. Smoot	2813	

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	SEAR	CHED		
Class	Subclass	Date	Examiner	
438	458	7/24/2004	sws	
438	459	7/24/2004	sws	1
438	463	7/24/2004	sws	
438	479	7/24/2004	sws	
438	940	7/24/2004	sws	
438	977	7/24/2004	sws	\

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Key Words: Gallium Nitride - GaN; Growth Substrate - Sapphire, Silicon Carbide, SiC;	7/24/2004	J.W.J. sws	
Laser - Ablate, Remove, separate.	7/24/2004	SWS.	
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		LW.S.	
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	7/24/2004	sws	